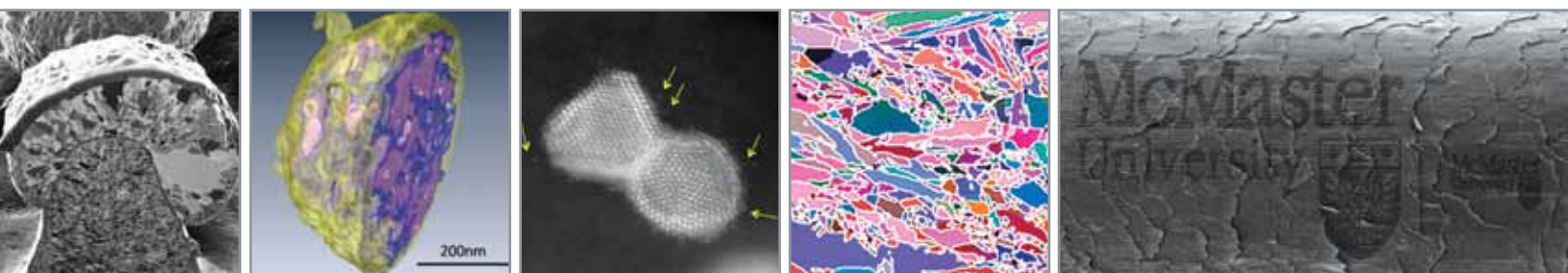


Advances in Electron Microscopy

A ONE-DAY EVENT to inform the local community of the latest advances in electron microscopy imaging methods and related technology. Program will include a keynote speaker and several technical talks on developments by microscope manufacturers. An ideal opportunity to learn the latest information on instrumentation, meet the manufacturers and network with other users from industry and universities in Southern Ontario.



Friday, Nov., 5, 2010

10:00 a.m. - 4:30 p.m.

Gilmour Hall 111, Council Chambers
McMaster University, Hamilton ON

4:30 p.m. - 6:00 p.m.

Meet and mingle at the CCEM

REGISTRATION

Event is FREE but registration is required by November 2, 2010. Places are limited, for registration and updated program, please see visit our website below.

KEYNOTE SPEAKER: DAVID JOY

Oak-Ridge National Laboratory and
University of Tennessee

**TITLE: *21st Century Scanning Microscopy -
Electrons and Ions***

TECHNICAL PRESENTATIONS:

- In-situ techniques
- Cross-sectional polishing
- New detectors for chemical analysis
- Orientation imaging
- Cryo electron microscopy

CONFIRMED MANUFACTURERS:

JEOL; Hitachi High Technologies; Hysitron;
Oxford Instruments; SFR-FEI and Zeiss

<http://ccem.mcmaster.ca/outreach-courses>



**Brockhouse Institute
for Materials Research**



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